

NLG4307

12.5 Gb/s 16 : 1 MUX

The NLG4307 is an ultra-fast 16:1 multiplexer. NLG4307 combines 16 parallel input signals operating at up to 781.25Mb/s into a single serial output signal as fast as 12.5 Gb/s (MIN.).

It was designed with LSCFL (Low-power Source Coupled FET Logic).

Owing to built-in 50-ohm termination resistors, external termination resistors are unnecessary for impedance matching.

The NLG4307 is fabricated using the 0.15- μ m gate length A-SAINT (Advanced Self-Aligned Implantation for N⁺ layer Technology) process.

FEATURES

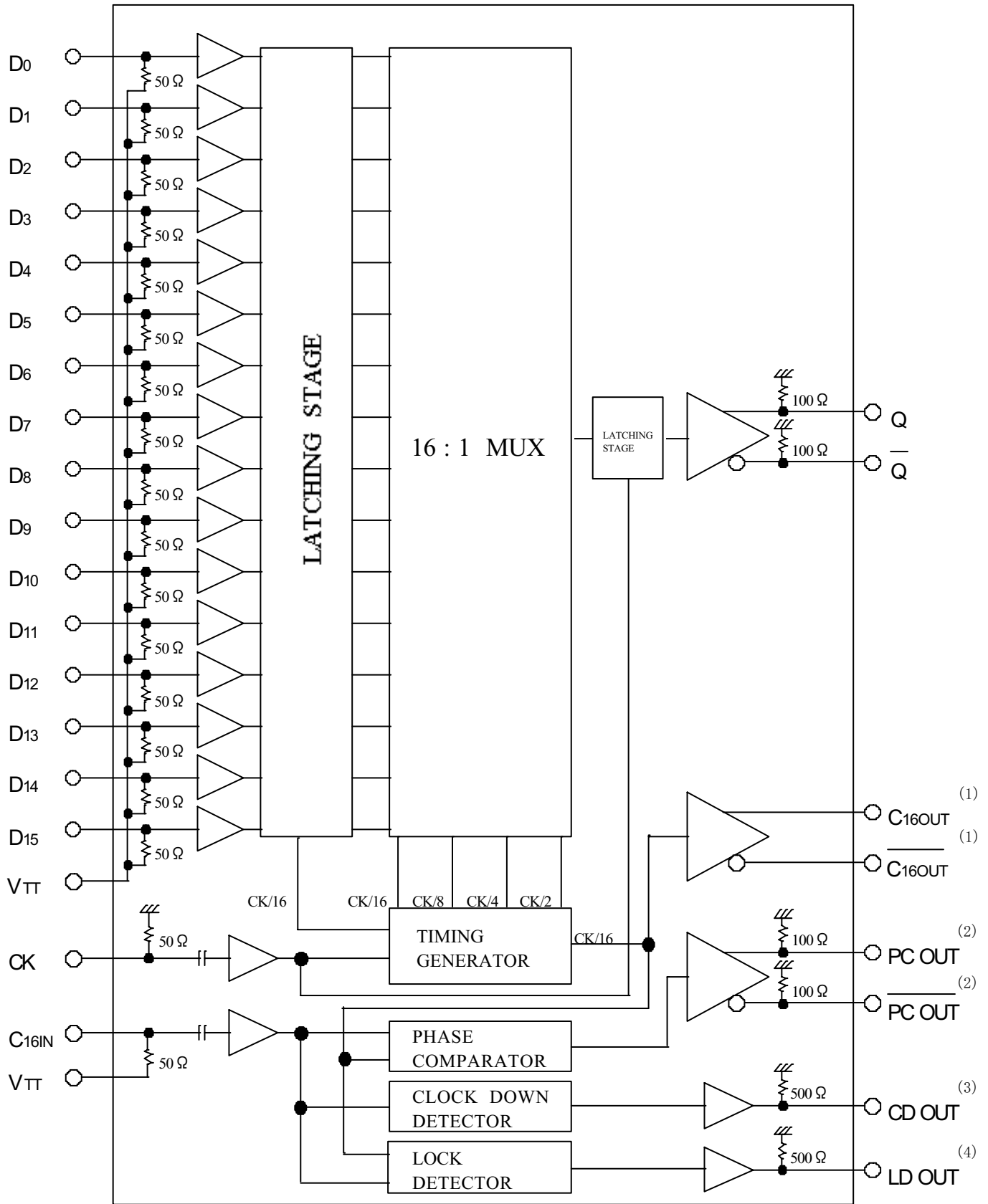
Ultra-high speed : maximum clock frequency	f_{MAX} : 12.5 GHz	[MIN.]
minimum clock frequency	f_{MIN} : 2.0 GHz	[MAX.]
output rise time	t_r = 35 ps (20-80%)	[TYP.]
output fall time	t_f = 30 ps (20-80%)	[TYP.]

High reliability : Hermetically-sealed package

APPLICATIONS

- Parallel-to-serial converters
- Pulse pattern generators
- Digital transmission system transmitters
- Computer links
- Board links

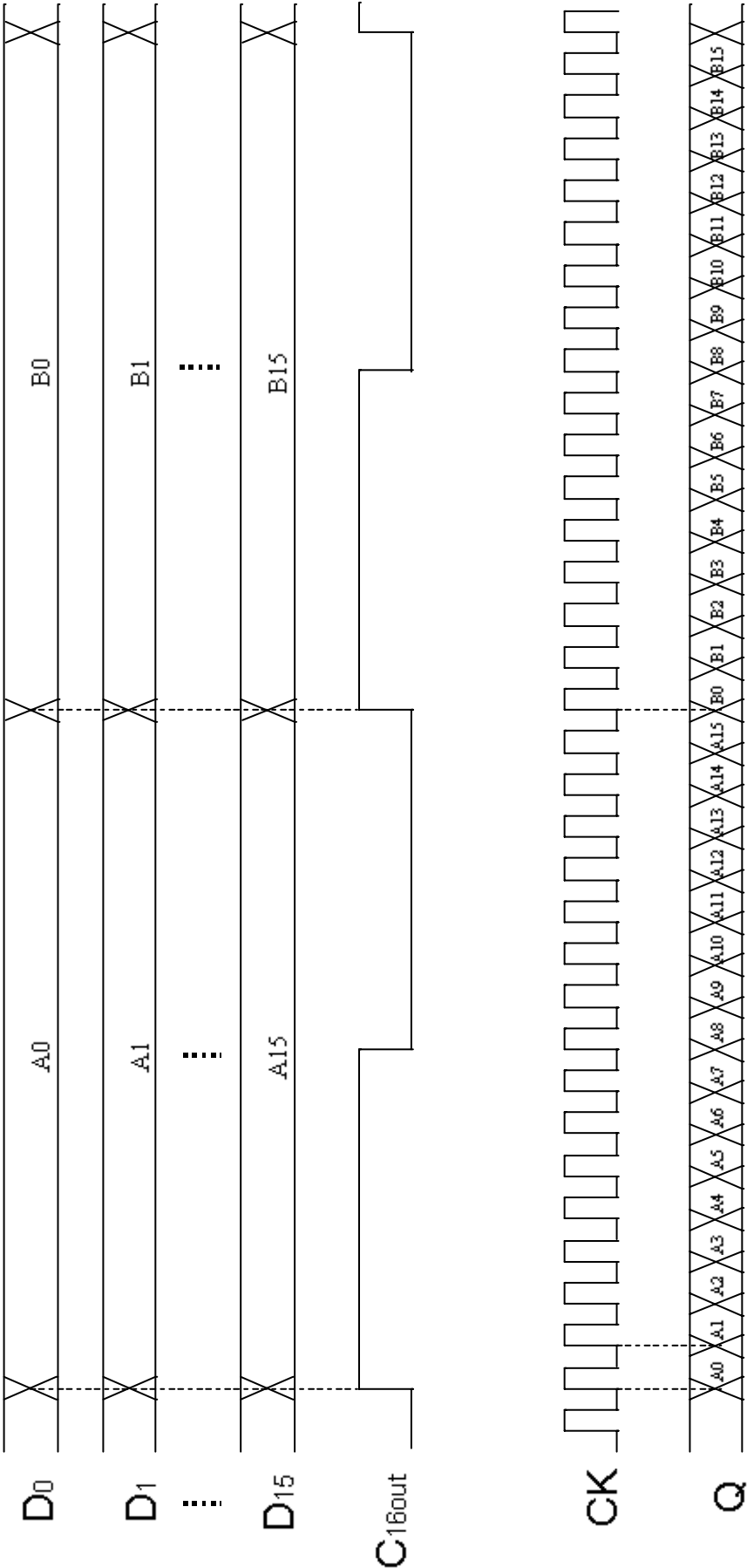
FUNCTIONAL DIAGRAM



Notes

- (1) 1/16 clock output terminals. (ECL output)
- (2) Phase comparator output terminals.
- (3) Clock down detector output terminal.
- (4) Lock detector output terminal.

TIMING CHART



PIN CONNECTION TABLE

No.	NAME	FUNCTION	No.	NAME	FUNCTION
1	GND	Ground (0.0V)	43	GND	Ground (0.0V)
2	V _{TT}	Input Signal Termination Power Supply (- 2.0 V)	44	V _{TT}	Input Signal Termination Power Supply (- 2.0 V)
3	GND	Ground (0.0V)	45	GND	Ground (0.0V)
4	D ₁	1/16 Data Input 1	46	D ₂	1/16 Data Input 2
5	GND	Ground (0.0V)	47	GND	Ground (0.0V)
6	D ₉	1/16 Data Input 9	48	D ₁₀	1/16 Data Input 10
7	GND	Ground (0.0V)	49	GND	Ground (0.0V)
8	D ₅	1/16 Data Input 5	50	D ₆	1/16 Data Input 6
9	GND	Ground (0.0V)	51	GND	Ground (0.0V)
10	D ₁₃	1/16 Data Input 13	52	D ₁₄	1/16 Data Input 14
11	GND	Ground (0.0V)	53	GND	Ground (0.0V)
12	D ₁₅	1/16 Data Input 15	54	D ₁₂	1/16 Data Input 12
13	GND	Ground (0.0V)	55	GND	Ground (0.0V)
14	D ₇	1/16 Data Input 7	56	D ₄	1/16 Data Input 4
15	GND	Ground (0.0V)	57	GND	Ground (0.0V)
16	D ₁₁	1/16 Data Input 11	58	D ₈	1/16 Data Input 8
17	GND	Ground (0.0V)	59	GND	Ground (0.0V)
18	D ₃	1/16 Data Input 3	60	D ₀	1/16 Data Input 0
19	GND	Ground (0.0V)	61	GND	Ground (0.0V)
20	V _{TT}	Input Signal Termination Power Supply (- 2.0 V)	62	V _{SS}	Power Supply (- 3.5 V)
21	GND	Ground (0.0V)	63	GND	Ground (0.0V)
22	GND	Ground (0.0V)	64	GND	Ground (0.0V)
23	V _{ref01}	1/16 Data Input Ref. 1 (1)	65	LD OUT	Lock Detector Output (6)
24	GND	Ground (0.0V)	66	GND	Ground (0.0V)
25	V _{SS}	Power Supply (- 3.5 V)	67	PC OUT	Phase Comparator Output (Comp.) (5)
26	GND	Ground (0.0V)	68	GND	Ground (0.0V)
27	V _{ref1}	Clock Input Ref. (3)	69	PC OUT	Phase Comparator Output (True) (5)
28	GND	Ground (0.0V)	70	GND	Ground (0.0V)
29	CK	Clock Input	71	C ₁₆ OUT	1/16 Clock Output (Comp.) (7)
30	GND	Ground (0.0V)	72	GND	Ground (0.0V)
31	V _{SS}	Power Supply (- 3.5 V)	73	C ₁₆ OUT	1/16 Clock Output (True) (7)
32	GND	Ground (0.0V)	74	GND	Ground (0.0V)
33	Q	Data Output (True) (5)	75	V _{SS}	Power Supply (- 3.5 V)
34	GND	Ground (0.0V)	76	GND	Ground (0.0V)
35	\overline{Q}	Data Output (Comp.) (5)	77	C ₁₆ IN	1/16 Clock Input
36	GND	Ground (0.0V)	78	GND	Ground (0.0V)
37	V _{SS}	Power Supply (- 3.5 V)	79	V _{ref2}	1/16 Clock Input Ref. (4)
38	GND	Ground (0.0V)	80	GND	Ground (0.0V)
39	V _{ref02}	1/16 Data Input Ref. 2 (2)	81	CD OUT	1/16 Clock Down Detector Output (6)
40	GND	Ground (0.0V)	82	GND	Ground (0.0V)
41	T _{CMON}	Case Temperature Monitor	83	V _{SS}	Power Supply (- 3.5 V)
42	GND	Ground (0.0V)	84	GND	Ground (0.0V)

Notes

See Page 5.

PIN CONNECTION TABLE

Notes

- (1) $V_{ref\ 01}$: Internally generated reference voltage that determines the data input ($D_1, D_3, D_5, D_7, D_9, D_{11}, D_{13}, D_{15}$) threshold level. By applying - 1.6 to - 1.0V externally to this pin, an arbitrary data input threshold voltage can be established.
- (2) $V_{ref\ 02}$: Internally generated reference voltage that determines the data input ($D_0, D_2, D_4, D_6, D_8, D_{10}, D_{12}, D_{14}$) threshold level. By applying - 1.6 to - 1.0V externally to this pin, an arbitrary data input threshold voltage can be established.
- (3) $V_{ref\ 1}$: Internally generated reference voltage that determines the clock input threshold level.
By applying - 2.1 to - 1.55 V externally to this pin, an arbitrary clock input threshold voltage can be established.
- (4) $V_{ref\ 2}$: Internally generated reference voltage that determines the 1/16 clock input threshold level.
By applying - 2.05 to - 1.47 V externally to this pin, an arbitrary 1/16 clock input threshold voltage can be established.
- (5) Terminate unused output pins to GND through 50-ohm resistors.
- (6) Terminate unused output pins to GND through 500-ohm resistor.
- (7) Terminate unused output pins to -2 V through 50-ohm resistors.

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING
V _{SS}	Power Supply Voltage	+0.5 V ~ - 4.0 V
V _{TT}	Termination Voltage	+0.5 V ~ - 2.5 V
V _{in}	Applied Voltage Amplitude at Clock Inputs (CK, C16IN)	1.6 V _{p-p}
V _{indin}	Applied Voltage at Data Inputs (D0 ~ D15)	+0.3 V ~ - 2.5 V
V _{inck1}	Applied Voltage at Clock Input (CK)	+ 1.6 V ~ - 1.6 V
V _{inck2}	Applied Voltage at 1/16 Clock Input (C16IN)	+0.3 V ~ - 2.5 V
V _{out}	Applied Voltage at Signal Outputs (Q, \overline{Q} , PC OUT, \overline{PC} OUT, CD OUT, LD OUT)	+0.2 V ~ - 1.75 V
V _{oute}	Applied Voltage at Signal Outputs (C16OUT, $\overline{C16OUT}$)	+0.2 V ~ - 2.5 V
V _{ref01} , V _{ref02}	Applied Voltage at Vref01 and Vref02 pins	+0.3 V ~ - 2.5 V
V _{ref1} , V _{ref2}	Applied Voltage at Vref1 and Vref2 pins under Bias	- 1.0 V ~ - 2.5 V
V _{TCMON}	Applied Voltage at Case Temperature Monitor pin	- 1.0 V ~ + 1.0 V
T _{stor}	Storage Temperature	- 60 °C ~ +150 °C
T _c ⁽¹⁾	Case Temperature under Bias	- 60 °C ~ +125 °C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
V _{SS}	Power Supply Voltage	- 3.75	- 3.5	- 3.4	V
V _{TT}	Termination Voltage		- 2.0		V
V _{ref01} , V _{ref02}	Data Input Reference Voltage	Adjust in the range from -1.6 V to -1.0 V			V
V _{ref1}	Clock Input Reference Voltage	Normally Open			V
V _{ref2}	1/16 Clock Input Reference Voltage	Normally Open			V
D _n (n = 0 ~ 15)	Data Input Interface	DC Coupling 50 Ω to V _{TT} (See DC Characteristics)			—
CK	Clock Input Interface	DC Coupling (See DC Characteristics) or AC Coupling (See AC Characteristics)			—
C16IN	1/16 Clock Input Interface	DC Coupling 50 Ω to V _{TT} (See pages 10, 11)			—
OUT	Data Output, Phase Comparator Output Interface (Q, \overline{Q} , PC OUT, \overline{PC} OUT)	DC Coupling, Terminate to GND through 50 Ω			—
	1/16 Clock Output Interface (C16OUT, $\overline{C16OUT}$)	DC Coupling, Terminate to V _{TT} through 50 Ω			—
	Clock Down Detector Output Interface (CD OUT)	DC Coupling, Terminate to GND through 500 Ω			—
	Lock Detector Output Interface (LD OUT)	DC Coupling, Terminate to GND through 500 Ω			—
T _{CMON}	Case Temperature Monitor	Connect to a DC voltmeter for estimating case temperature. Relationship between TCMON and case temperature is shown in page 22.			—

Notes

(1) T_c : temperature at package base.

DC CHARACTERISTICS

(VSS = -3.75 V ~ -3.4 V, VTT = -2.0 V, GND = 0.0 V, Tc = 0 ~ 75°C⁽¹⁾)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
V _{OH}	Output Voltage, High ($\overline{Q}, \overline{Q}$)	- 0.15	0.0		V
V _{OL}	Output Voltage, Low ($\overline{Q}, \overline{Q}$)		- 0.9	- 0.80	V
V _{OHE}	Output Voltage, High ($\overline{C_{16OUT}}, \overline{C_{16OUT}}$)	- 0.98	- 0.75		V
V _{OLE}	Output Voltage, Low ($\overline{C_{16OUT}}, \overline{C_{16OUT}}$)		- 1.8	- 1.74	V
V _{IH}	Input Voltage, High (CK)	- 0.1	0.0		V
V _{IL}	Input Voltage, Low (CK)		- 0.9	- 0.8	V
V _{IHE}	Input Voltage, High (D ₀ ~ D ₁₅ , C _{16in})	- 1.17	- 0.9		V
V _{ILE}	Input Voltage, Low (D ₀ ~ D ₁₅ , C _{16in})	V _{TT}	- 1.7	- 1.48	V
I _{SS}	Power Supply Current (V _{SS})		1.2	1.77	A
I _{TT}	Power Supply Current (V _{TT})		0.24	0.53 ⁽²⁾	A
P _d	Power Dissipation		4.2	6.64	W

(3)

AC CHARACTERISTICS

(VSS = -3.75 V ~ -3.4 V, VTT = -2.0 V, GND = 0.0 V, Tc = 0 ~ 75°C⁽¹⁾, Vref01 : Adjust in the range from -1.6 V to -1.0 V, Vref02 : Adjust in the range from -1.6 V to -1.0 V, Vref1 : Open, Vref2 : Open)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
V _{in}	Minimum Clock Input Voltage Amplitude (CK)			0.7	V _{p-p}
V _{OH}	Output Voltage, High ($\overline{Q}, \overline{Q}$)	- 0.13	0.0		V
V _{OL}	Output Voltage, Low ($\overline{Q}, \overline{Q}$)		- 0.9	- 0.82	V
V _{amp}	Output Voltage Amplitude ($\overline{Q}, \overline{Q}$)	0.76	1.00		V _{p-p}
f _{MAX}	Maximum Clock Frequency	12.5			GHz
f _{MIN}	Minimum Clock Frequency			2.0	GHz
t _r	Output Rise Time ($\overline{Q}, \overline{Q}$ 20-80%)		35	50	ps
t _f	Output Fall Time ($\overline{Q}, \overline{Q}$ 20-80%)		30	45	ps
t _{rc}	Output Rise Time ($\overline{C_{16OUT}}, \overline{C_{16OUT}}$ 20-80%)		180	300	ps
t _{fc}	Output Fall Time ($\overline{C_{16OUT}}, \overline{C_{16OUT}}$ 20-80%)		110	200	ps
t _{dLH}	Output Rise Delay (CK - $\overline{Q}, \overline{Q}$)	375	415	450	ps
t _{dHL}	Output Fall Delay (CK - $\overline{Q}, \overline{Q}$)	375	415	450	ps
t _{dLH}	Output Rise Delay (CK - $\overline{C_{16OUT}}, \overline{C_{16OUT}}$)	560	630	705	ps
t _{dHL}	Output Fall Delay (CK - $\overline{C_{16OUT}}, \overline{C_{16OUT}}$)	555	630	710	ps
t _{Sd}	Minimum Setup Time (D _n - $\overline{C_{16OUT}}$)		0.44	0.51	ns
t _{Hd}	Minimum Hold Time ($\overline{C_{16OUT}}$ - D _n)		-0.25	-0.16	ns
PM	Phase Margin	280			deg.

(4)

(5)

(5)

(5)

(5)

(5)

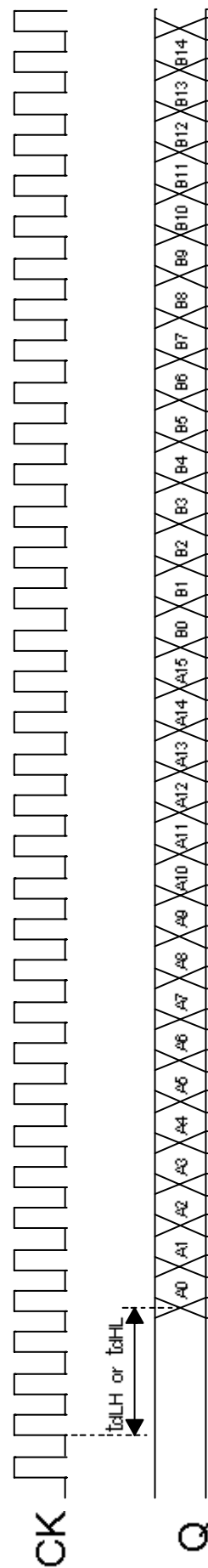
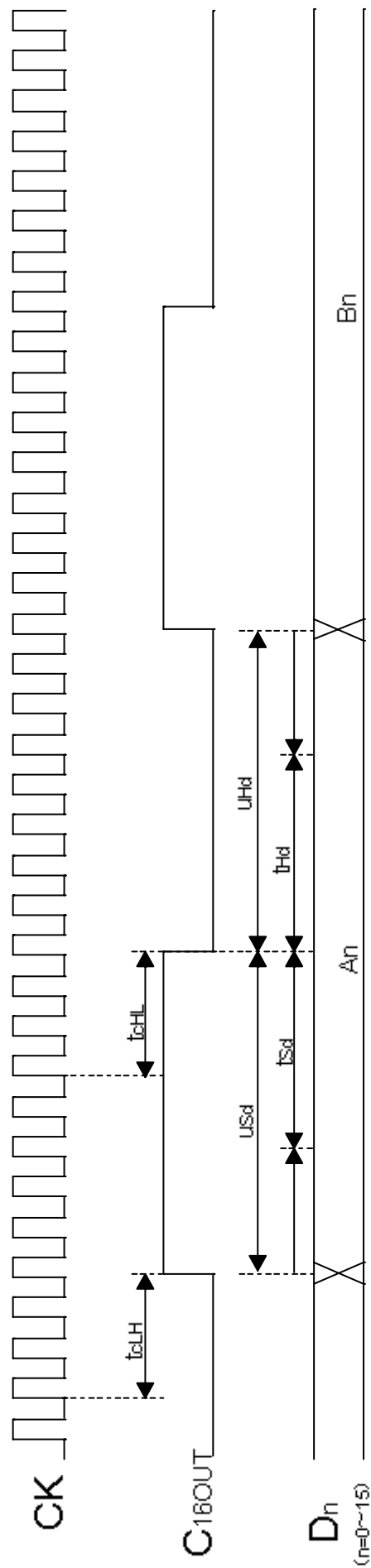
(5)

(6)

Notes

- (1) Tc : temperature at package base.
- (2) I_{TT} (MAX.) : D₀ ~ D₁₅, C_{16IN} = - 0.8 V
- (3) P_d = V_{SS} × I_{SS}. Excludes current through input termination resistors and ECL output FETs.
- (4) Confirmed by error-free operation using a pseudo-random pattern having a word length of 2²³-1 bits.
- (5) See page 9.
- (6) PM = { (1 / f) - (tsd + thd) } × f × 360

TIMING CHART (INCLUDING DELAY TIMES)



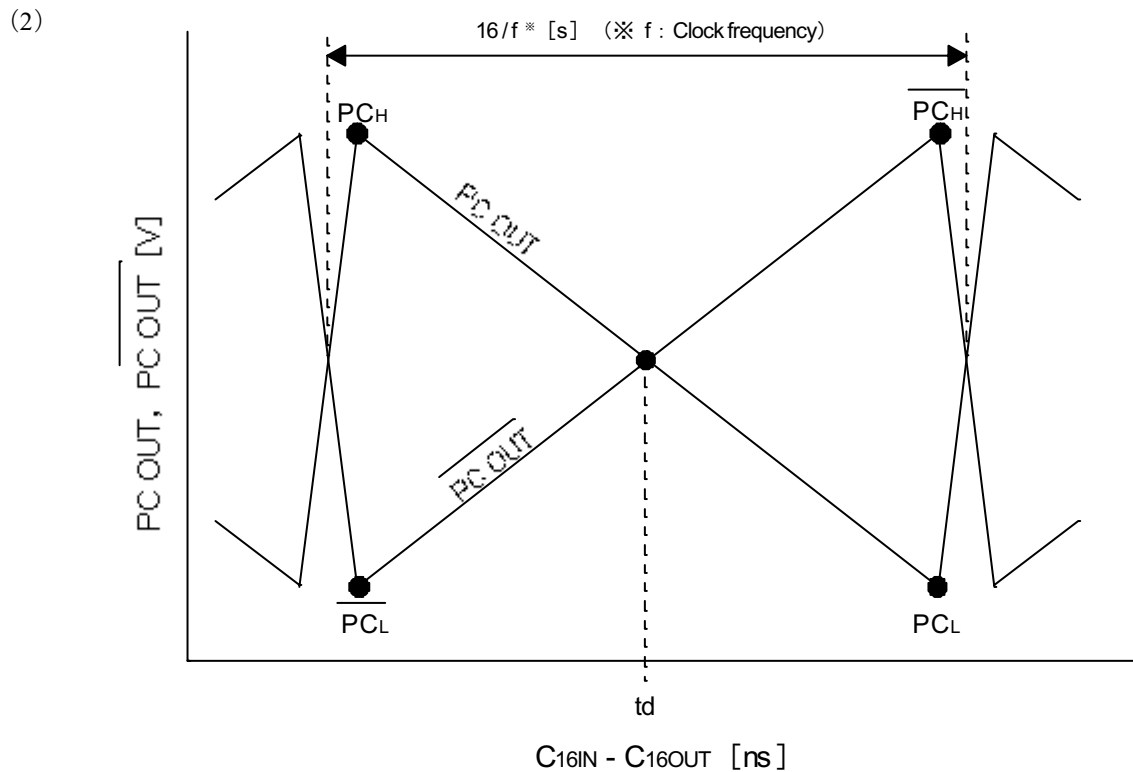
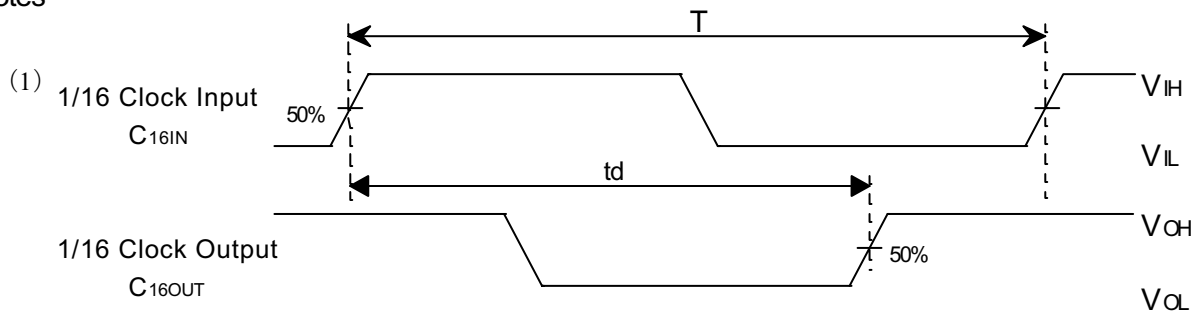
(See the timing chart on page 3 for a more complete logical description. Here, t_{sD} and t_{hD} are the minimum setup and hold times as defined on the previous page; t_{sD} and t_{hD} are the corresponding user setup and hold times.)

PHASE COMPARATOR CHARACTERISTICS

($V_{SS} = -3.75\text{ V} \sim -3.4\text{ V}$, $V_{TT} = -2.0\text{ V}$, $GND = 0.0\text{ V}$, $T_c = 0 \sim 75^\circ\text{C}$, V_{ref01} : Adjust in the range from -1.6 V to -1.0 V , V_{ref02} : Adjust in the range from -1.6 V to -1.0 V , V_{ref1} : Open, V_{ref2} : Open, $C_{16IN} = 0.8\text{Vp-p}$)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS	
t_d	1/16 Clock Delay (C16IN - C16OUT)	$T/2+0.25$	$T/2+0.4$	$T/2+0.55$	ns	(1),(2)
PC_H	Phase Comparator Output Voltage, High (PC OUT)	-0.2	-0.1		V	(2)
PC_L	Phase Comparator Output Voltage, Low (PC OUT)		-1.20	-0.75	V	(2)
\overline{PC}_H	Phase Comparator Output Voltage, High ($\overline{PC OUT}$)	-0.2	-0.1		V	(2)
\overline{PC}_L	Phase Comparator Output Voltage, Low ($\overline{PC OUT}$)		-1.20	-0.75	V	(2)

Notes



CLOCK DOWN DETECTOR CHARACTERISTICS

(VSS = -3.75 V ~ -3.4 V, VTT = -2.0 V, GND = 0.0 V, Tc = 0 ~ 75 °C, Vref01 : Adjust in the range from -1.6 V to -1.0 V, Vref02 : Adjust in the range from -1.6 V to -1.0 V, Vref1 : Open, Vref2 : Open)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
CD _H	Clock Down Detector Output Voltage, High	-0.3	-0.2		V
CD _L	Clock Down Detector Output Voltage, Low		-0.7	-0.45	V

(1)

(2)

Notes

- (1) Measurement Condition
1/16 clock input amplitude : C_{16IN} = 0.8 Vp-p

- (2) Measurement Condition
1/16 clock input amplitude : C_{16IN} = 0 Vp-p

LOCK DETECTOR CHARACTERISTICS

(VSS = -3.75 V ~ -3.4 V, VTT = -2.0 V, GND = 0.0 V, Tc = 0 ~ 75 °C, Vref01 : Adjust in the range from -1.6 V to -1.0 V, Vref02 : Adjust in the range from -1.6 V to -1.0 V, Vref1 : Open, Vref2 : Open, C_{16IN}=0.8Vp-p)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
LD _H	Lock Detector Output Voltage High	-0.10	-0.05		V
LD _L	Lock Detector Output Voltage Low		-1.40	-1.00	V

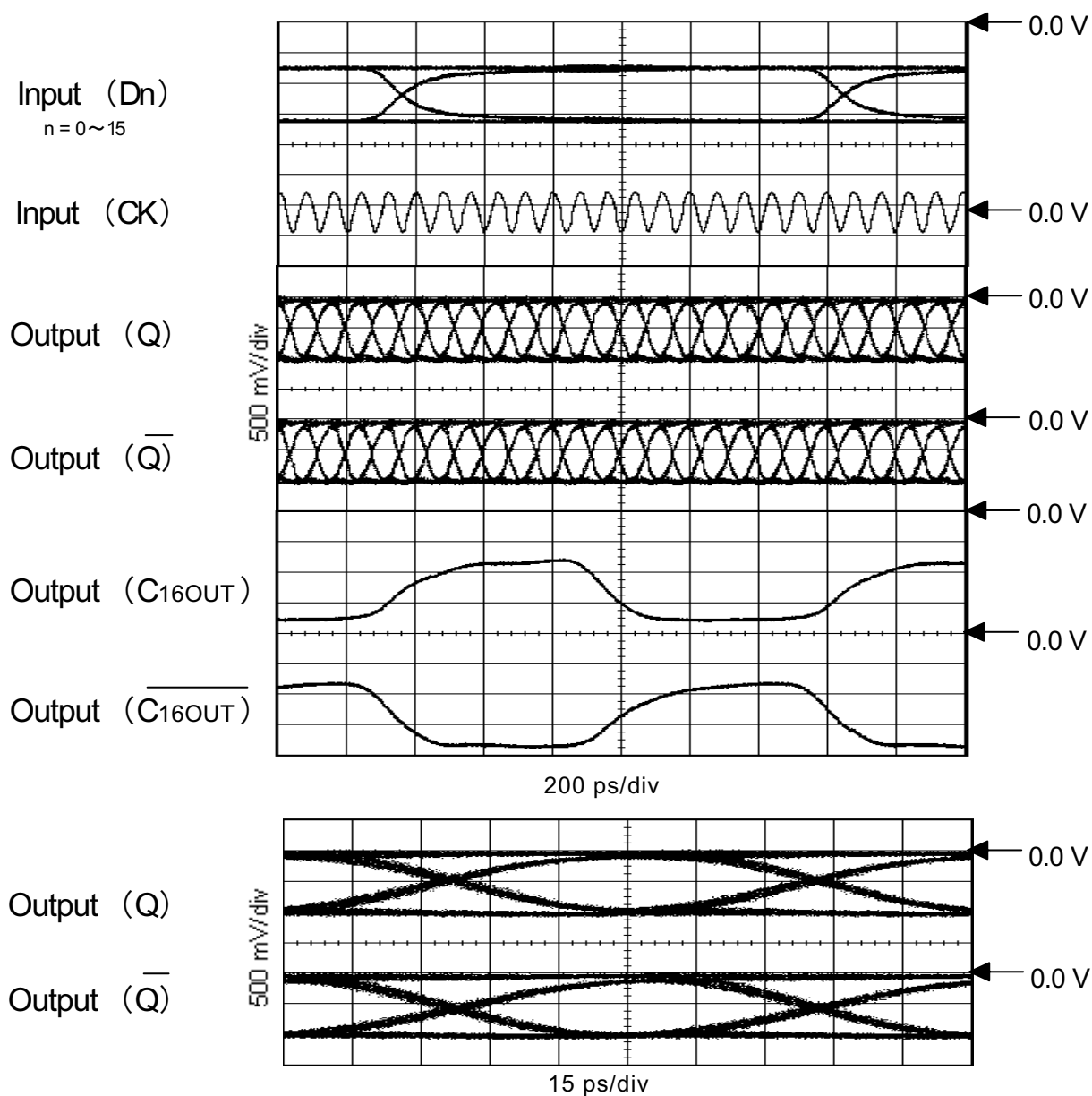
Notes

FUNCTION	SYMBOL
$f_{in} \times m = f_{out} \times n$ (m,n:integer)	LD _H or LD _L
$f_{in} \neq f_{out}$ $f_{out}/2 < f_{in} < f_{out} \times 2$	$\frac{LD_H + LD_L}{2}$

f_{in} : C_{16in} frequency [GHz]

f_{out} : C_{16out} frequency [GHz]

INPUT AND OUTPUT WAVEFORMS (12.5 Gb/s)

Measurement Conditions

$V_{SS} = -3.5 \text{ V}$

$V_{TT} = -2.0 \text{ V}$

V_{ref01} : Open

V_{ref02} : Open

V_{ref1} : Open

V_{ref2} : Open

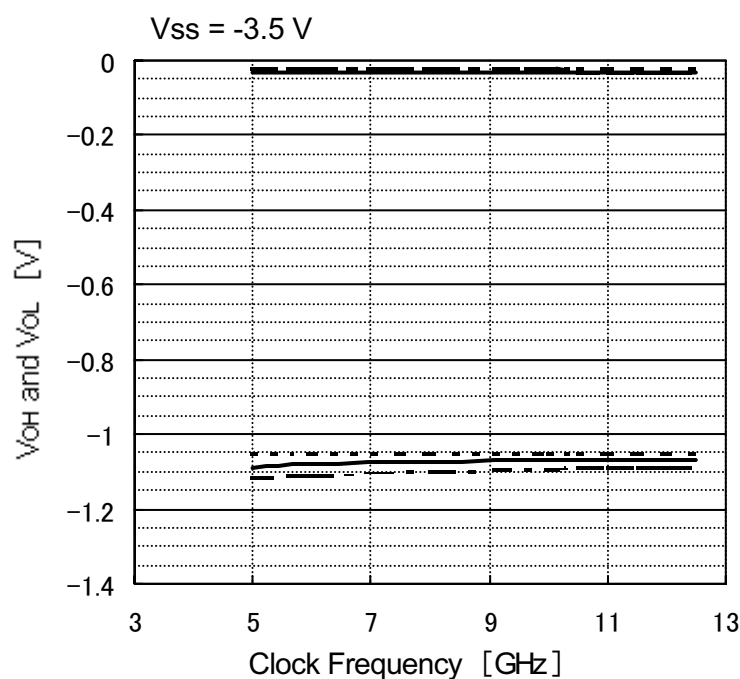
D_n ($n=0\sim15$) : 781.25 Mb/s, PN = 31, $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : 12.5 GHz, $V_{in} = 0.7 \text{ V}_{p-p}$, AC coupling,

$T_c = 75^\circ\text{C}$

Data outputs connected to the 50-ohm impedance pins of a sampling oscilloscope.

ECL outputs (C16OUT, C16OUT-bar) connected to the 50-ohm impedance pins of a sampling oscilloscope via ECL terminators. Results given here were obtained using the NEL test fixture.

SAMPLE AC CHARACTERISTICS (Q, \overline{Q})

..... : $T_c = 0 \text{ }^{\circ}\text{C}$
 ————— : $T_c = 25 \text{ }^{\circ}\text{C}$
 - - - - - : $T_c = 75 \text{ }^{\circ}\text{C}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

Dn : $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : $V_{in} = 0.7 \text{ V}_{p-p}$

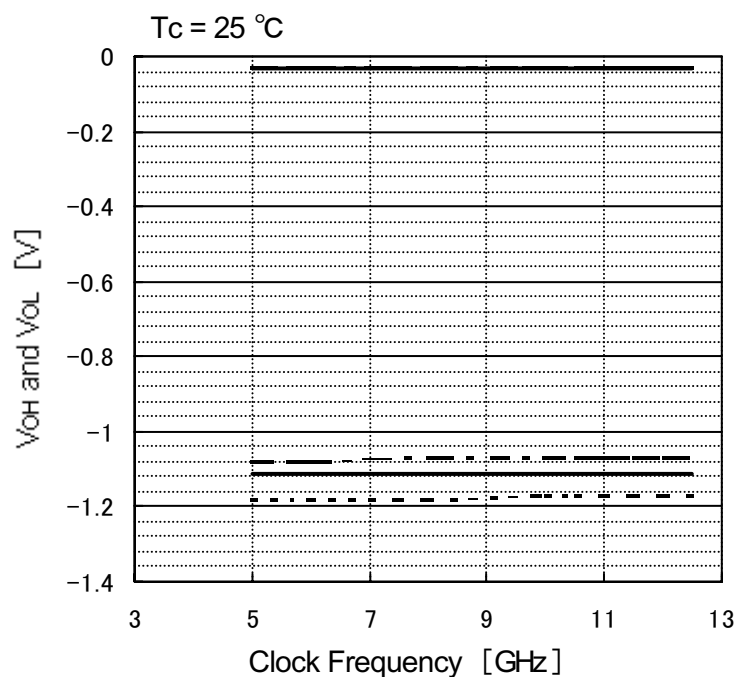
Vref01 : Open

Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.



..... : $V_{SS} = -3.4 \text{ V}$
 ————— : $V_{SS} = -3.5 \text{ V}$
 - - - - - : $V_{SS} = -3.75 \text{ V}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

Dn : $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : $V_{in} = 0.7 \text{ V}_{p-p}$

Vref01 : Open

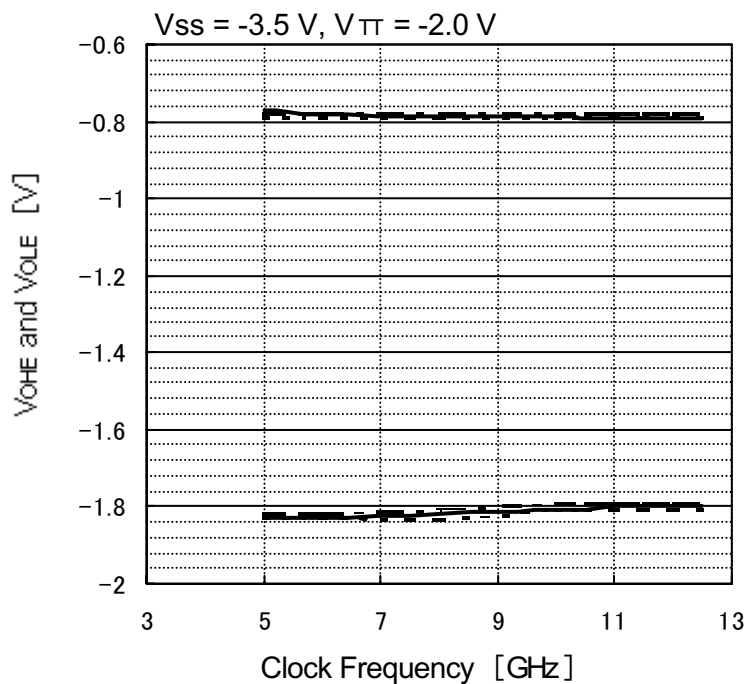
Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.

SAMPLE AC CHARACTERISTICS (C16OUT, C16OUT)



- - - - - : $T_c = 0 \text{ }^{\circ}\text{C}$
 ————— : $T_c = 25 \text{ }^{\circ}\text{C}$
 - . - . - : $T_c = 75 \text{ }^{\circ}\text{C}$

Measurement Conditions

Dn : $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : $V_{in} = 0.7 \text{ V}_{p-p}$

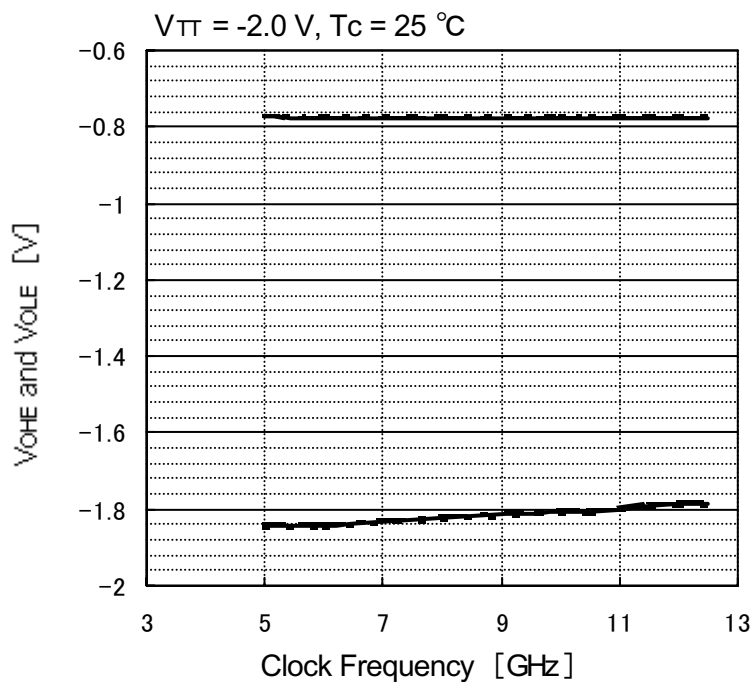
Vref01 : Open

Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.



- - - - - : $V_{SS} = -3.4 \text{ V}$
 ————— : $V_{SS} = -3.5 \text{ V}$
 - . - . - : $V_{SS} = -3.75 \text{ V}$

Measurement Conditions

Dn : $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : $V_{in} = 0.7 \text{ V}_{p-p}$

Vref01 : Open

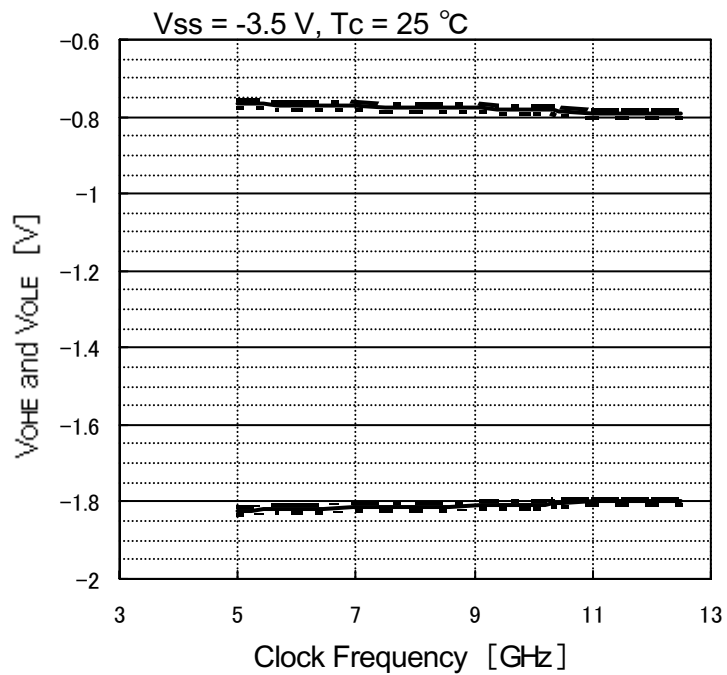
Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.

SAMPLE AC CHARACTERISTICS (C16OUT, C16OUT)



----- : $V_{TT} = -1.9 \text{ V}$
 ----- : $V_{TT} = -2.0 \text{ V}$
 ----- : $V_{TT} = -2.1 \text{ V}$

Measurement Conditions

Dn : $V_{IH} = -1.0 \text{ V}$, $V_{IL} = -1.7 \text{ V}$

CK : $V_{in} = 0.7 \text{ V}_{p-p}$

Vref01 : Open

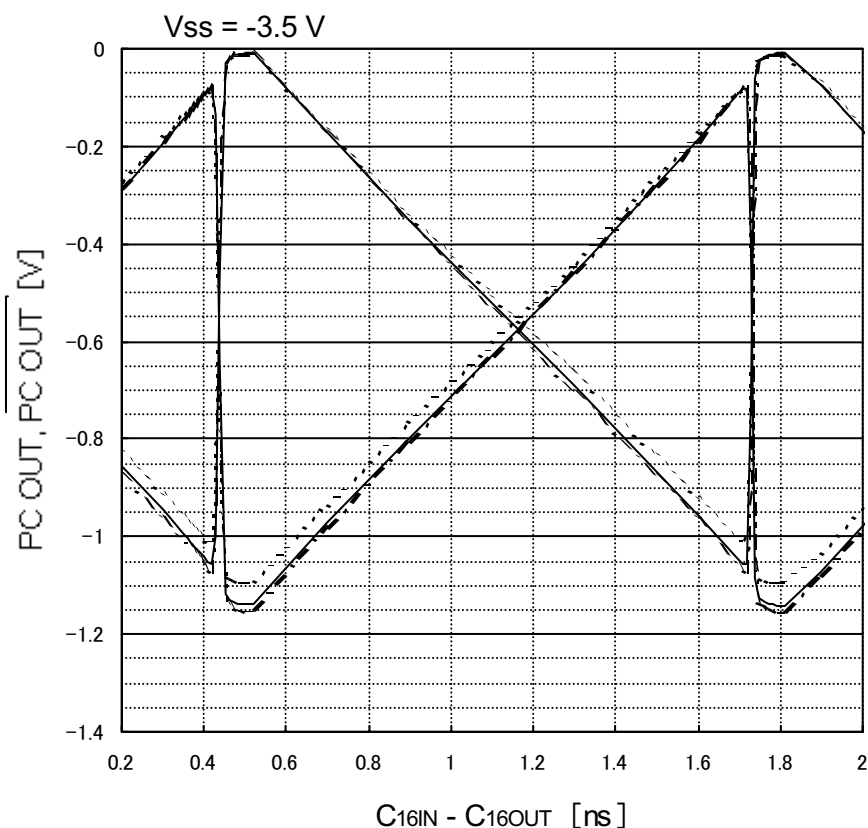
Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.

SAMPLE PHASE COMPARATOR CHARACTERISTICS



----- : $T_c = 0 \text{ }^{\circ}\text{C}$
 _____ : $T_c = 25 \text{ }^{\circ}\text{C}$
 - . - . - : $T_c = 75 \text{ }^{\circ}\text{C}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

$D_n : 781.25 \text{ Mb/s,}$

$V_{IH} = -1.0 \text{ V, } V_{IL} = -1.7 \text{ V}$

$CK : 12.5 \text{ GHz, } V_{in} = 0.7 \text{ Vp-p}$

$C_{16IN} : 781.25 \text{ MHz, } V_{in} = 0.8 \text{ Vp-p}$

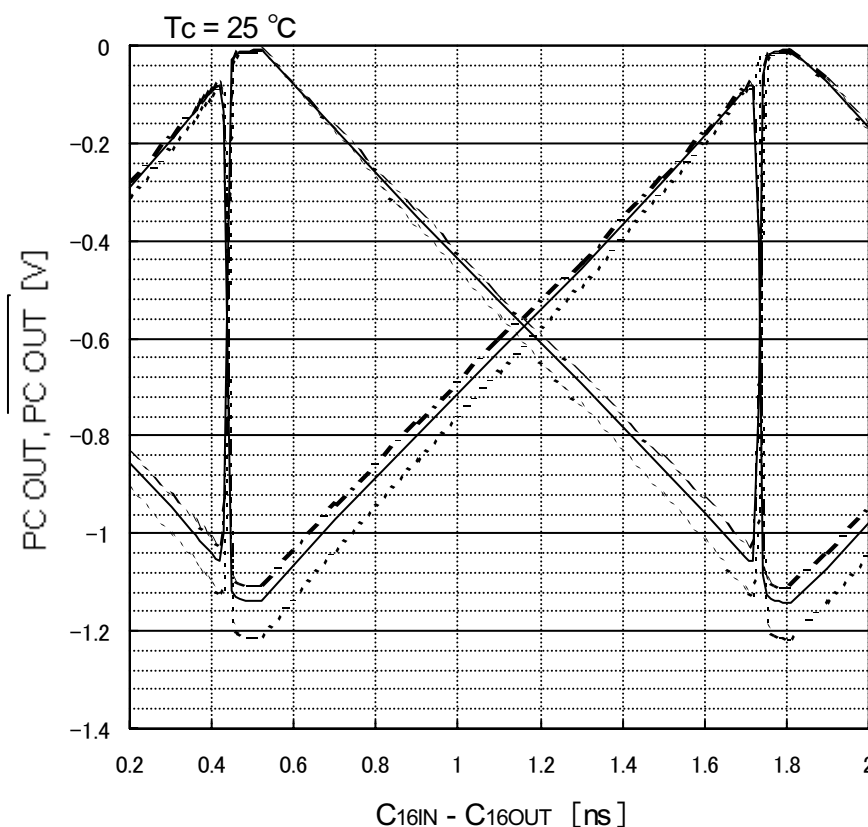
$V_{ref01} : \text{Open}$

$V_{ref02} : \text{Open}$

$V_{ref1} : \text{Open}$

$V_{ref2} : \text{Open}$

Results given here were obtained using the NEL test fixture.



----- : $V_{SS} = -3.4 \text{ V}$
 _____ : $V_{SS} = -3.5 \text{ V}$
 - . - . - : $V_{SS} = -3.75 \text{ V}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

$D_n : 781.25 \text{ Mb/s,}$

$V_{IH} = -1.0 \text{ V, } V_{IL} = -1.7 \text{ V}$

$CK : 12.5 \text{ GHz, } V_{in} = 0.7 \text{ Vp-p}$

$C_{16IN} : 781.25 \text{ MHz, } V_{in} = 0.8 \text{ Vp-p}$

$V_{ref01} : \text{Open}$

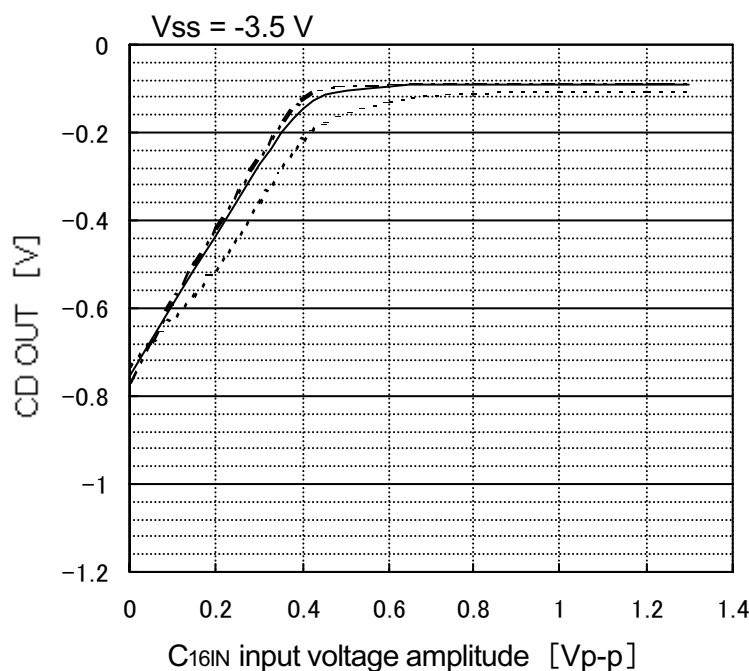
$V_{ref02} : \text{Open}$

$V_{ref1} : \text{Open}$

$V_{ref2} : \text{Open}$

Results given here were obtained using the NEL test fixture.

SAMPLE CLOCK DOWN DETECTOR CHARACTERISTICS



..... : $T_c = 0 \text{ }^{\circ}\text{C}$
 ————— : $T_c = 25 \text{ }^{\circ}\text{C}$
 - - - - - : $T_c = 75 \text{ }^{\circ}\text{C}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

$D_n : 781.25 \text{ Mb/s,}$

$V_{IH} = -1.0 \text{ V, } V_{IL} = -1.7 \text{ V}$

$CK : 12.5 \text{ GHz, } V_{in} = 0.7 \text{ Vp-p}$

$C_{16IN} : 781.25 \text{ MHz}$

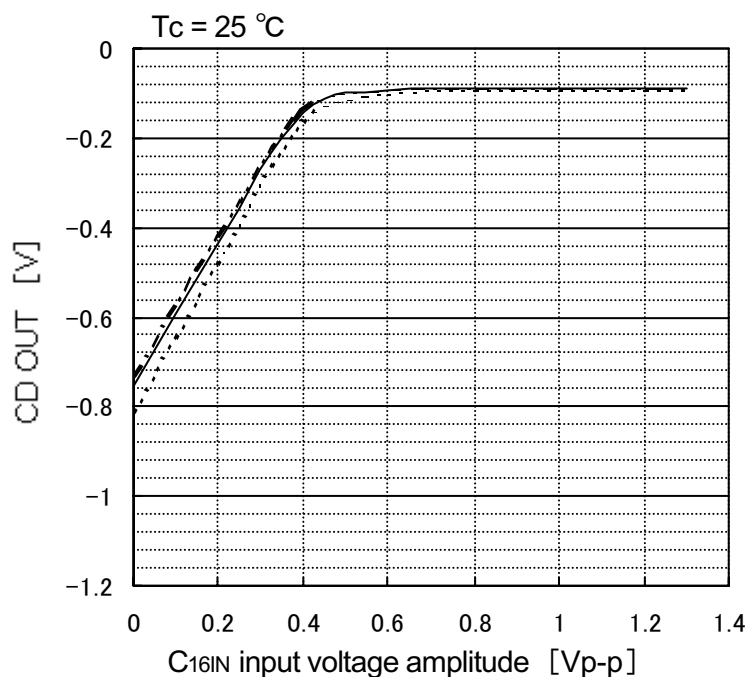
$V_{ref01} : \text{Open}$

$V_{ref02} : \text{Open}$

$V_{ref1} : \text{Open}$

$V_{ref2} : \text{Open}$

Results given here were obtained using the NEL test fixture.



..... : $V_{SS} = -3.4 \text{ V}$
 ————— : $V_{SS} = -3.5 \text{ V}$
 - - - - - : $V_{SS} = -3.75 \text{ V}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

$D_n : 781.25 \text{ Mb/s,}$

$V_{IH} = -1.0 \text{ V, } V_{IL} = -1.7 \text{ V}$

$CK : 12.5 \text{ GHz, } V_{in} = 0.7 \text{ Vp-p}$

$C_{16IN} : 781.25 \text{ MHz}$

$V_{ref01} : \text{Open}$

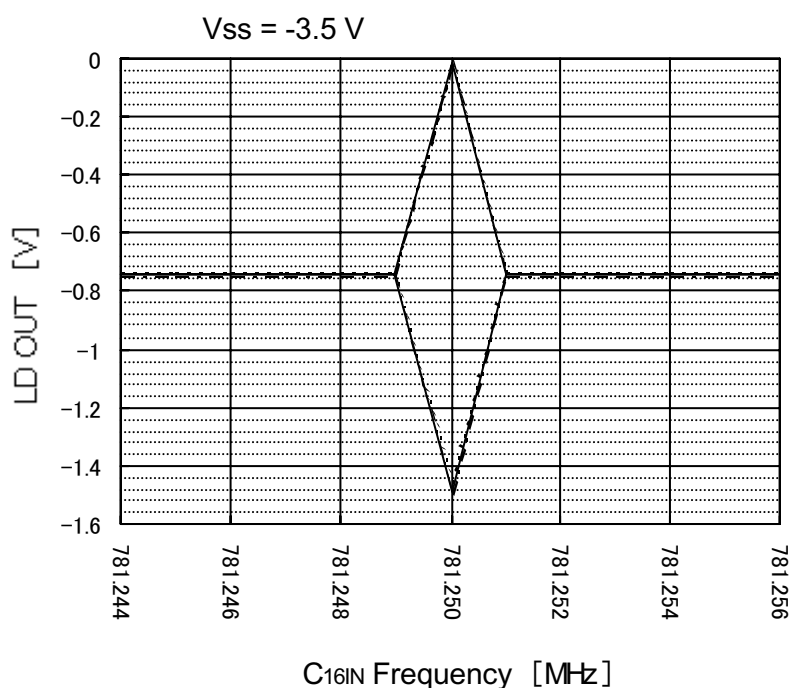
$V_{ref02} : \text{Open}$

$V_{ref1} : \text{Open}$

$V_{ref2} : \text{Open}$

Results given here were obtained using the NEL test fixture.

SAMPLE LOCK DETECTOR CHARACTERISTICS



..... : $T_c = 0 \text{ }^{\circ}\text{C}$
 _____ : $T_c = 25 \text{ }^{\circ}\text{C}$
 - - - - - : $T_c = 75 \text{ }^{\circ}\text{C}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

CK : 12.5 GHz, $V_{in} = 0.7 \text{ V}_{p-p}$

C16in=0.8Vp-p

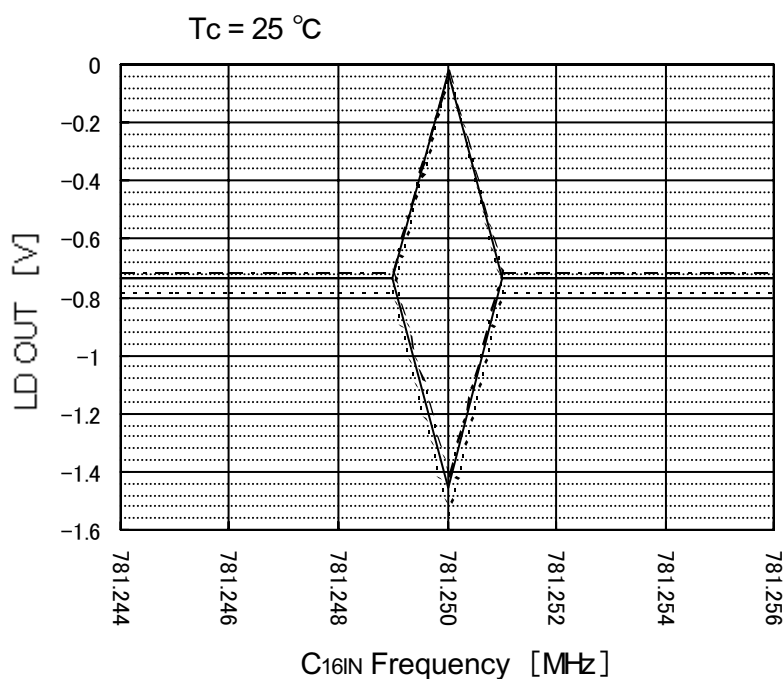
Vref01 : Open

Vref02 : Open

Vref1 : Open

Vref2 : Open

Results given here were obtained using the NEL test fixture.



..... : $V_{SS} = -3.4 \text{ V}$
 _____ : $V_{SS} = -3.5 \text{ V}$
 - - - - - : $V_{SS} = -3.75 \text{ V}$

Measurement Conditions

$V_{TT} = -2.0 \text{ V}$

CK : 12.5 GHz, $V_{in} = 0.7 \text{ V}_{p-p}$

C16in=0.8Vp-p

Vref01 : Open

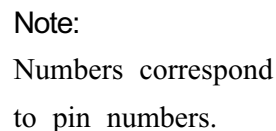
Vref02 : Open

Vref1 : Open

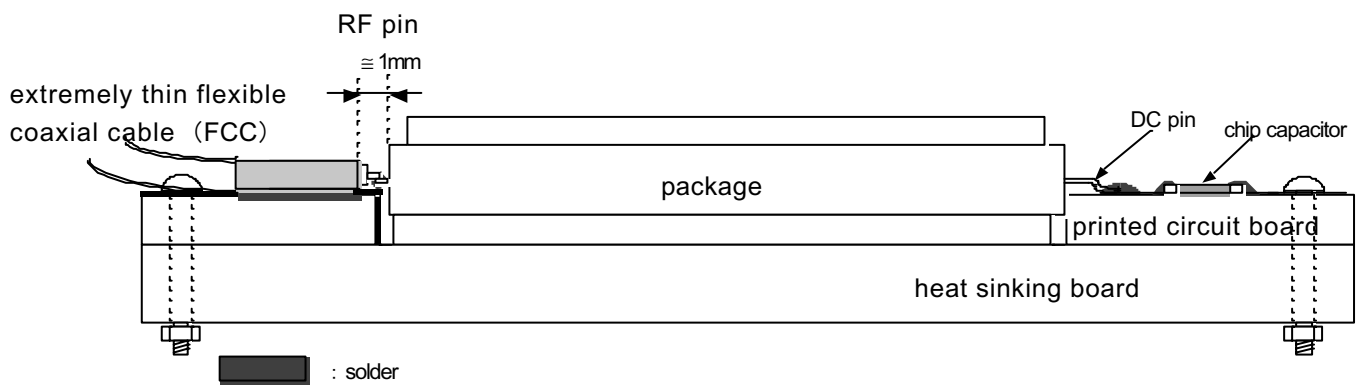
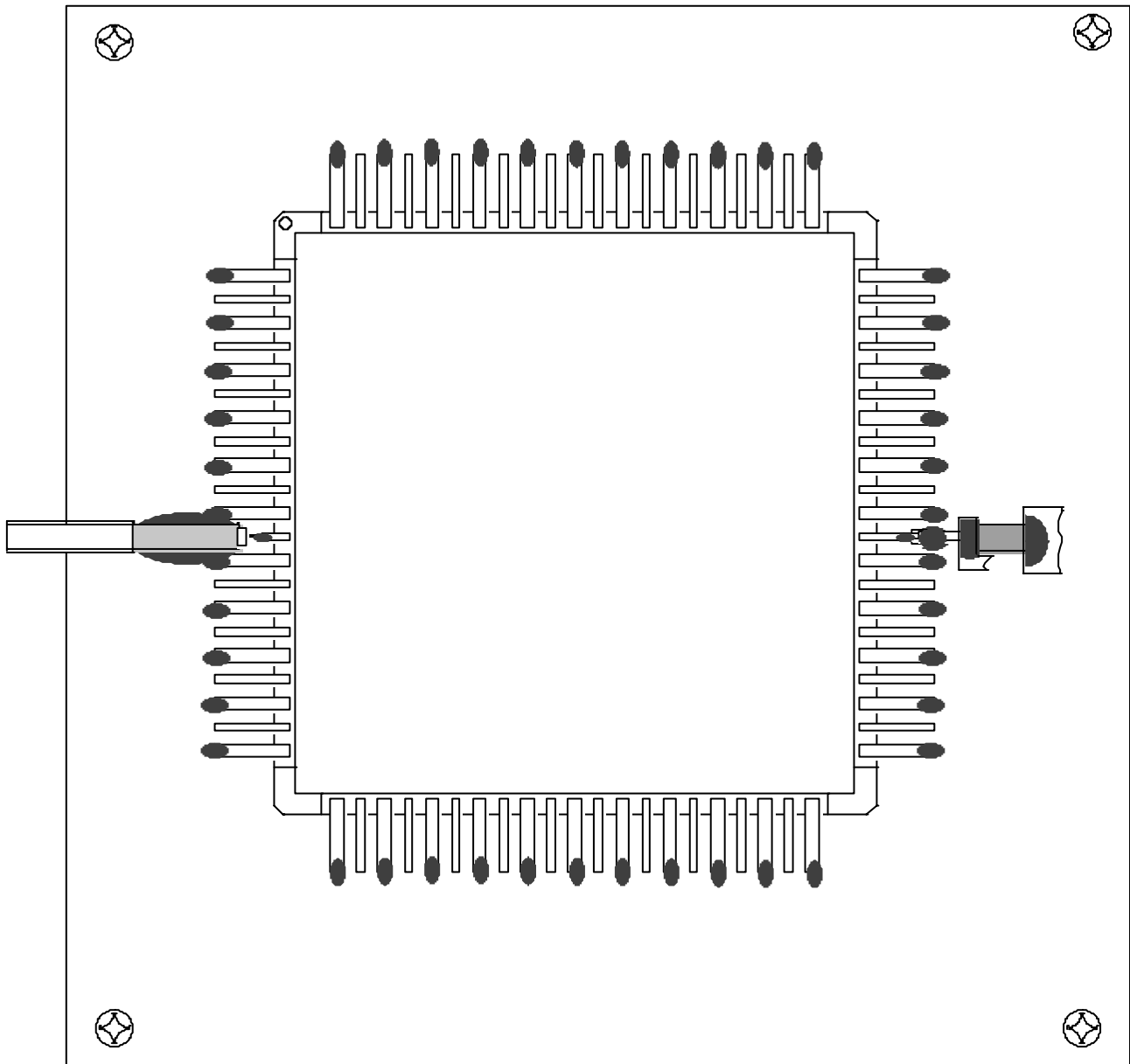
Vref2 : Open

Results given here were obtained using the NEL test fixture.

SAMPLE IMPLEMENTATION

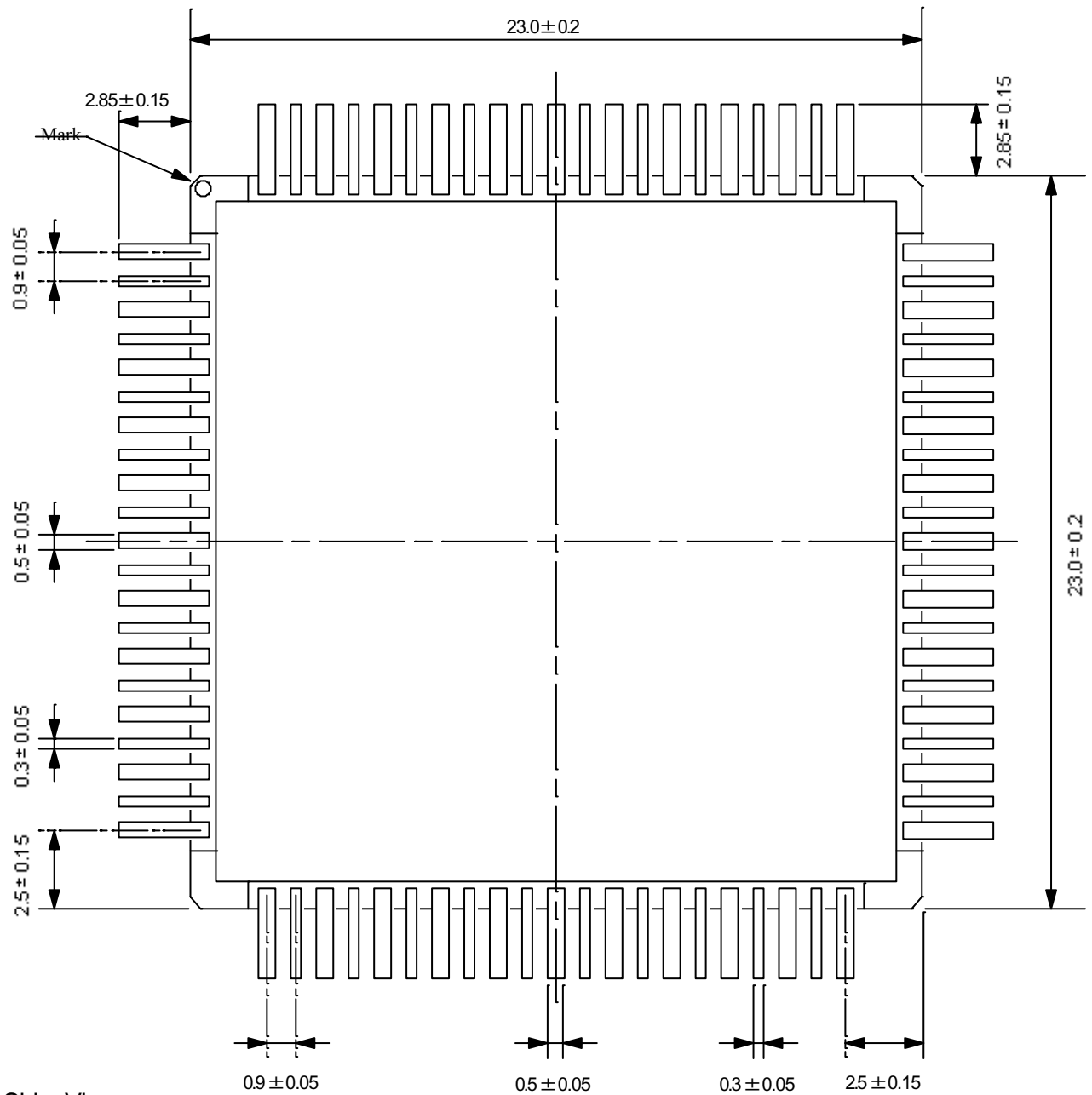
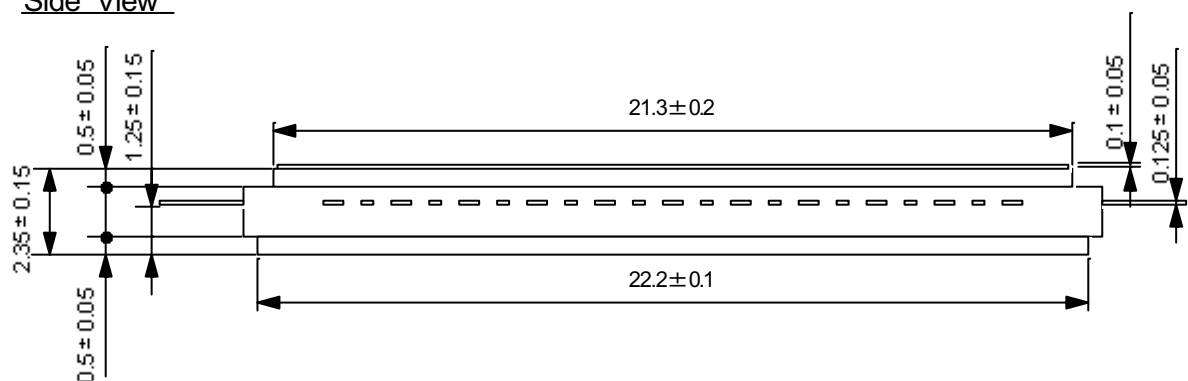


SAMPLE MOUNTING

le
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Caution : The package base should be connected to the ground.

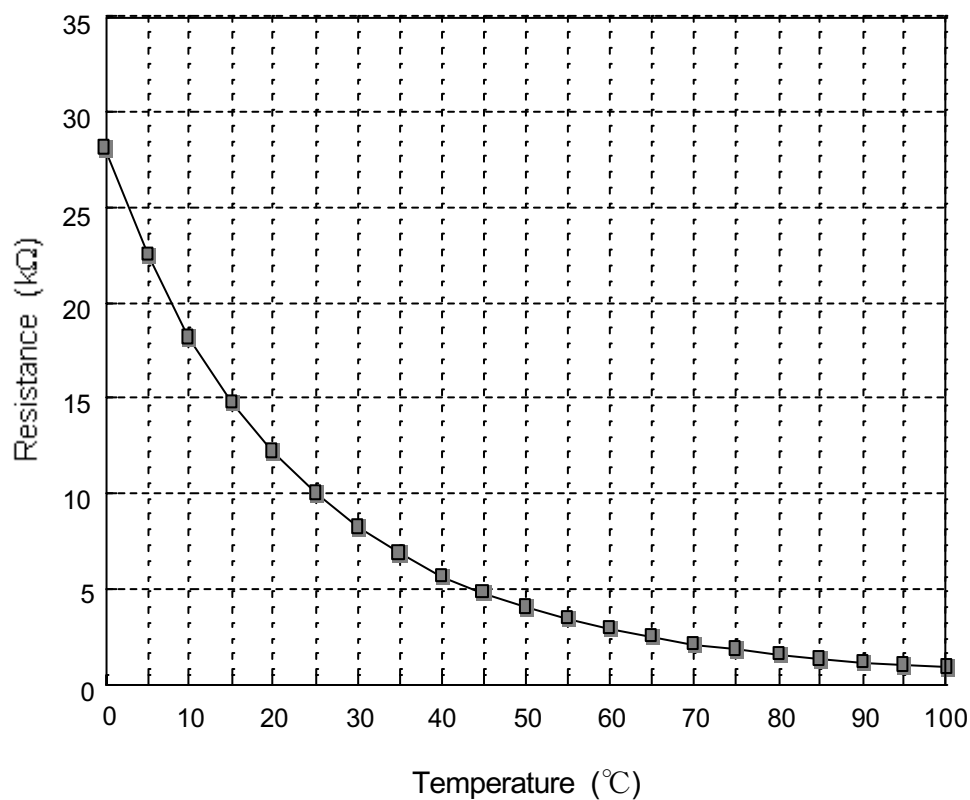
TB 84 - PIN PACKAGE DIMENSION (mm)

Top ViewSide View

SAMPLE TEMPERATURE MONITOR

TCMON Resistance Value Versus Case Temperature

TEMPERATURE (°C)	RESISTANCE (kΩ)	TEMPERATURE (°C)	RESISTANCE (kΩ)
	TYP.		TYP.
0	28.08	55	3.464
5	22.56	60	2.950
10	18.24	65	2.523
15	14.84	70	2.166
20	12.15	75	1.867
25	10.00	80	1.615
30	8.277	85	1.402
35	6.887	90	1.221
40	5.759	95	1.068
45	4.839	100	0.9362
50	4.085		



HANDLING INSTRUCTIONS

Since the NLG4307 is fabricated with GaAs MESFET's (Metal Semiconductor Field Effect Transistors), users are recommended to follow the instructions below to prevent damage to the chip from electro-static discharge.

(1) Power Supply Sequence

The following power supply sequence is recommended.

- 1) Set supply voltage V_{SS} , V_{TT} , V_{ref01} , V_{ref02} , V_{ref1} , V_{ref2} and GND to 0 V.
- 2) Apply V_{ref01} , V_{ref02} , V_{ref1} , V_{ref2} , V_{SS} and V_{TT} .

RF signals are recommended to be applied while power supplying and biasing.

(2) Handling Precautions

- 1) Use a conductive working desk connected to the ground (or, a conductive table top connected to the ground).
- 2) Require all handling personnel to wear a conductive bracelet or wrist-strap connected to the ground through a 1 M-ohm resistors.
- 3) Ground all test equipment.
- 4) Ground all soldering iron tips.
- 5) Store IC's and other devices such as chip capacitors in their conductive carriers until they are soldered.

NEL

NLG4307

MEMO

Caution

1. In order to improve products and technology, specifications are subject to change without notice.
2. When using the products, be sure the latest information and specifications are used.
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